


<b>Search Notes</b>  	<b>Application/Control No.</b>  10777102	<b>Applicant(s)/Patent Under Reexamination</b>  YUN ET AL.
	<b>Examiner</b>  Díaz, José R	<b>Art Unit</b>  2815

### SEARCHED

Class	Subclass	Date	Examiner
257	522	1/22/08	JRD
438	456,458	1/22/08	JRD
228	208	2/26/08	JRD

### SEARCH NOTES

Search Notes	Date	Examiner
TEXT search East. See search history printout.257/e27.111,e29.295; 438/455	1/22/08	JRD
TEXT search East. See search history printout.156/60,106,107	2/26/08	JRD

### INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
257	522,e27.111,e29.295	1/22/08	JRD
438	455,456,458	1/22/08	JRD